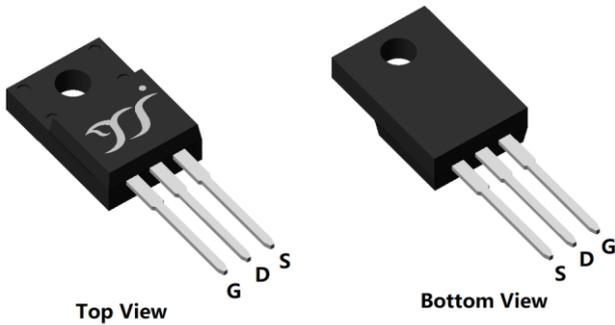
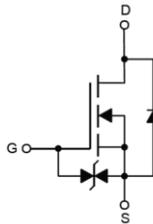


## N-Channel Enhancement Mode Field Effect Transistor



**ITO-220AB**



### Product Summary

- $V_{DS}$  800V
- $I_D$  19A
- $R_{DS(ON)}$  (at  $V_{GS}=10V$ ) <240m $\Omega$
- 100% EAS Tested
- 100%  $\nabla V_{DS}$  Tested

### General Description

- Excellent package for heat dissipation
- High density cell design for low  $R_{DS(ON)}$
- Epoxy Meets UL 94 V-0 Flammability Rating
- Halogen Free

### Applications

- Power switching application
- Uninterruptible power supply
- DC-DC converter

### Limiting Values

Parameter	Conditions	Symbol	Min	Max	Unit	
Drain-source Voltage		$V_{DS}$	-	800	V	
Gate-source Voltage		$V_{GS}$	-30	30		
Continuous Drain Current (Note 1,2)	Steady-State	$I_D$	$T_A=25^\circ C, V_{GS}=10V$	-	1.69	A
			$T_A=100^\circ C, V_{GS}=10V$	-	1.06	
Continuous Drain Current (Note 1,3)	Steady-State		$T_C=25^\circ C, V_{GS}=10V, \text{Chip limitation}$	-	19	
			$T_C=100^\circ C, V_{GS}=10V$	-	12	
Pulsed Drain Current	$T_C=25^\circ C, t_p \leq 10\mu s$	$I_{DM}$	-	45		
Maximum Body-Diode Continuous Current	$T_C=25^\circ C$	$I_S$	-	19		
Maximum Body-Diode Pulsed Current	$T_C=25^\circ C, t_p \leq 10\mu s$	$I_{SM}$	-	45		
Avalanche Energy (non-repetitive)	$T_J=25^\circ C, V_G=10V, R_G=25\Omega, L=30mH, I_{AS}=4.3A$	EAS	-	277.3	mJ	
Total Power Dissipation (Note 1,2)	Steady-State	$P_D$	$T_A=25^\circ C$	-	1.92	W
			$T_A=100^\circ C$	-	0.76	
Total Power Dissipation (Note 1,3)	Steady-State		$T_C=25^\circ C$	-	65	
			$T_C=100^\circ C$	-	26	
MOSFET dv/dt Ruggedness	$V_{DS}=0 \dots 400V, R_G=0\Omega$	dv/dt	-	47.6	V/ns	
Reverse Diode dv/dt	$V_{DS}=0 \dots 400V, I_D \leq 15A, di/dt=200A/\mu s$	dv/dt	-	16.6		
Maximum Diode Commutation Speed	$V_{DS}=0 \dots 400V, I_D \leq 15A, R_G=0\Omega$	dif/dt	-	7660	A/ $\mu s$	
Insulation withstand voltage	$V_{rms}, t=60s$	$V_{ISO}$	-	$\geq 4000$	V	
Junction and Storage Temperature Range		$T_J, T_{STG}$	-55	150	$^\circ C$	

### Thermal Resistance

Parameter	Symbol	Typ	Max	Units
Thermal Resistance Junction-to-Ambient (Note 2)	$R_{\theta JA}$	-	65	$^\circ C/W$
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	-	1.9	

### Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
YJF210C80BZJ	B1	YJF210C80B	50	/	5000	Tube



# YJF210C80BZJ

## ■ Electrical Characteristics

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V, I_D=250\mu A, T_j=25^\circ C$	800	-	-	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=800V, V_{GS}=0V, T_j=25^\circ C$	-	-	1	$\mu A$
		$V_{DS}=800V, V_{GS}=0V, T_j=150^\circ C$	-	-	100	
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 30V, V_{DS}=0V, T_j=25^\circ C$	-	-	$\pm 10$	$\mu A$
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A, T_j=25^\circ C$	2.2	3	3.8	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=8.5A, T_j=25^\circ C$	-	190	240	m $\Omega$
		$V_{GS}=10V, I_D=8.5A, T_j=150^\circ C$	-	530	670	
Diode Forward Voltage	$V_{SD}$	$I_S=19A, V_{GS}=0V, T_j=25^\circ C$	-	0.86	1.2	V
Gate Resistance	$R_G$	$f=1MHz, T_j=25^\circ C$	-	2.9	-	$\Omega$
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=400V, V_{GS}=0V, f=1MHz, T_j=25^\circ C$	-	2200	-	pF
Output Capacitance	$C_{oss}$		-	43	-	
Reverse Transfer Capacitance	$C_{rss}$		-	1.9	-	
Effective Output capacitance, Energy Related	$C_{o(er)}$	$V_{DS}=0\dots 400V, V_{GS}=0V, f=1MHz, T_j=25^\circ C$	-	58	-	
Effective Output Capacitance, Time Related	$C_{o(tr)}$		-	265	-	
<b>Switching Parameters</b>						
Total Gate Charge	$Q_g$	$V_{GS}=10V, V_{DS}=400V, I_D=16A, T_j=25^\circ C$	-	48.6	-	nC
Gate-Source Charge	$Q_{gs}$		-	10	-	
Gate-Drain Charge	$Q_{gd}$		-	17.5	-	
Reverse Recovery Charge	$Q_{rr}$	$I_F=16A, di/dt=100A/\mu s, V_{GS}=0V, V_R=400V, T_j=25^\circ C$	-	5713	-	nC
Reverse Recovery Time	$t_{rr}$		-	340	-	ns
Peak Reverse Recovery Current	$I_{rrm}$		-	28.5	-	A
Turn-on Delay Time	$t_{D(on)}$	$V_{GS}=10V, V_{DS}=400V, I_D=16A, R_{GEN}=3\Omega, T_j=25^\circ C$	-	38.6	-	ns
Turn-on Rise Time	$t_r$		-	20.6	-	
Turn-off Delay Time	$t_{D(off)}$		-	43.3	-	
Turn-off Fall Time	$t_f$		-	13.2	-	

### Note:

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- The value of  $R_{\theta JA}$  is measured with the device mounted on the 40mm\*40mm\*1.1mm single layer FR-4 PCB board with 1 in<sup>2</sup> pad of 2oz. Copper, in the still air environment with  $T_A=25^\circ C$ . The maximum allowed junction temperature of 150 $^\circ C$ . The value in any given application depends on the user's specific board design.
- Thermal resistance from junction to soldering point (on the exposed drain pad).



# YJF210C80BZJ

## Typical Electrical and Thermal Characteristics Diagrams

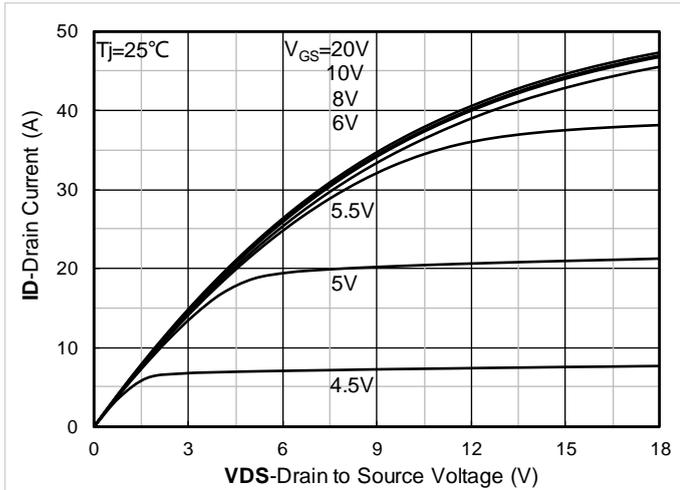


Figure 1. Output Characteristics; typical values

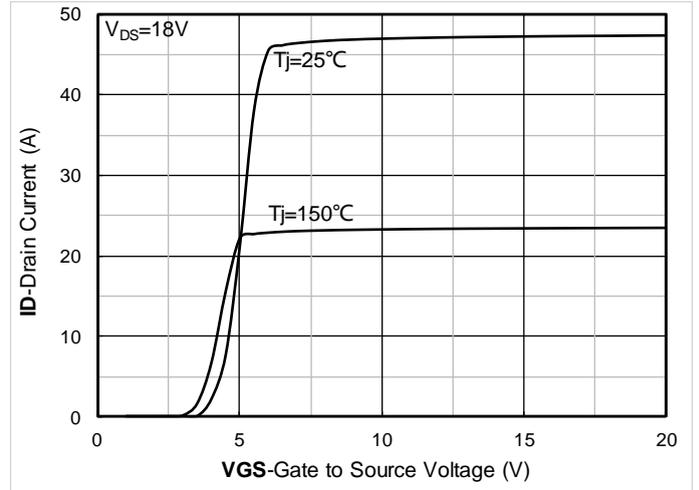


Figure 2. Transfer Characteristics; typical values

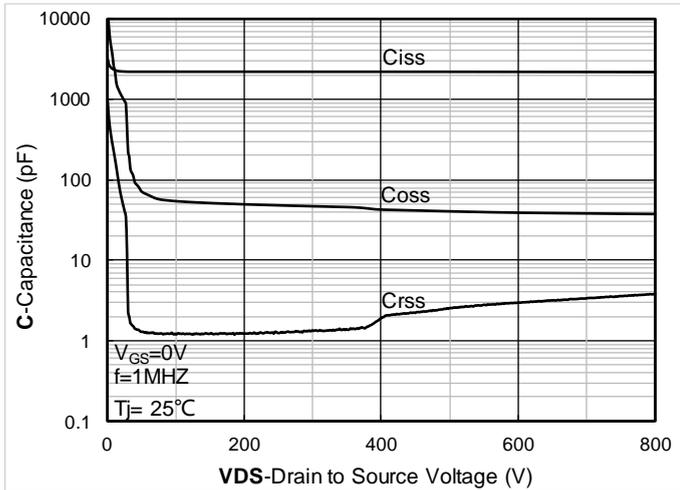


Figure 3. Capacitance Characteristics; typical values

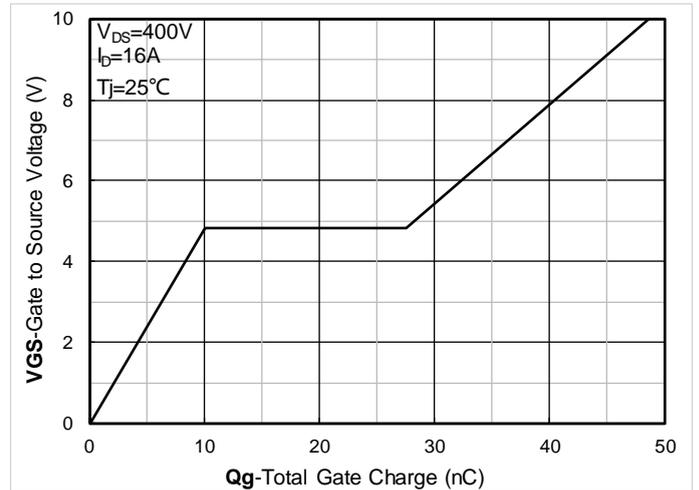


Figure 4. Gate Charge; typical values

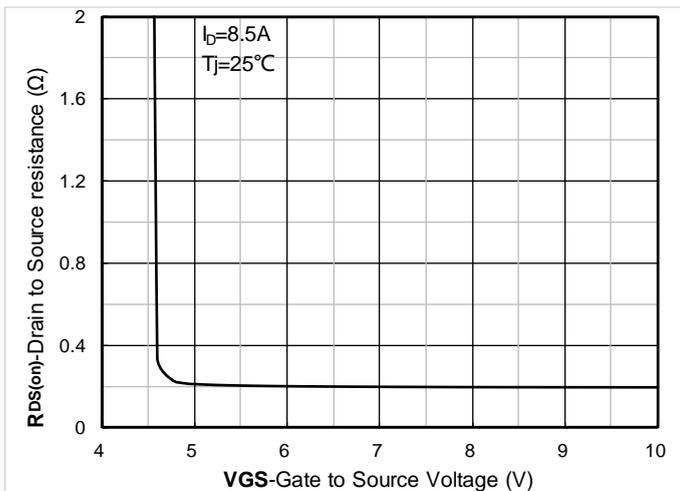


Figure 5. On-Resistance vs. Gate to Source Voltage; typical values

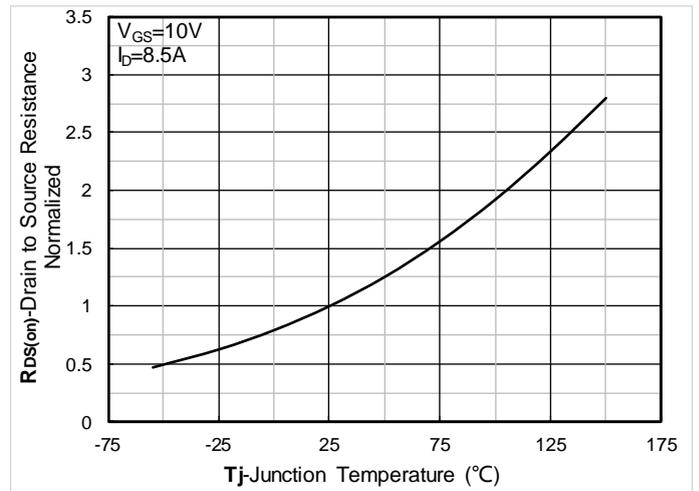


Figure 6. Normalized On-Resistance



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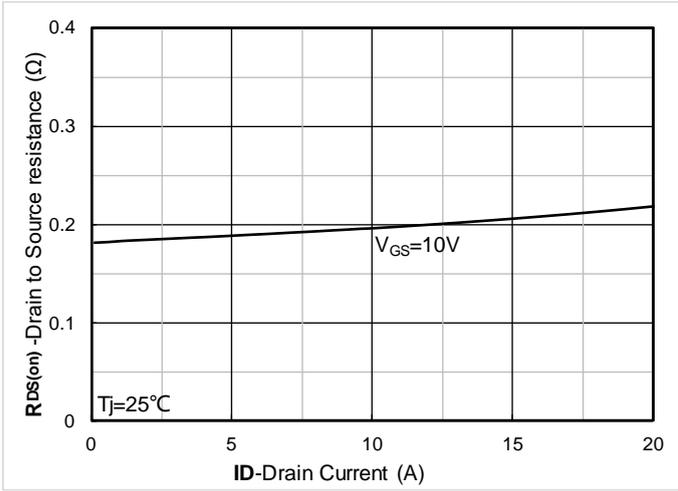


Figure 7. RDS(on) vs. Drain Current; typical values

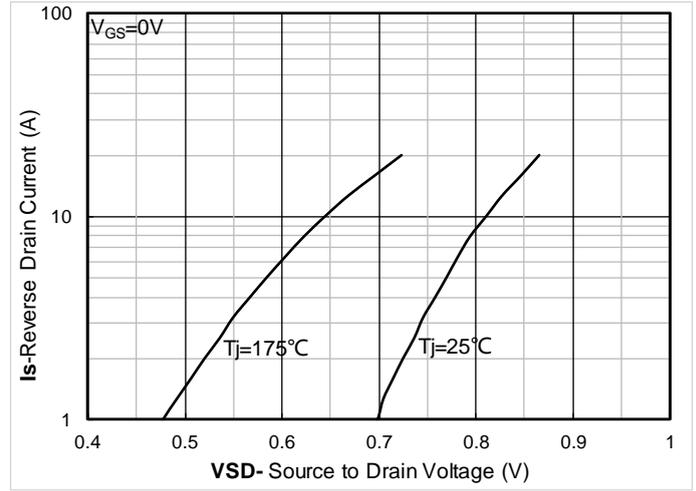


Figure 8. Forward characteristics of reverse diode; typical values

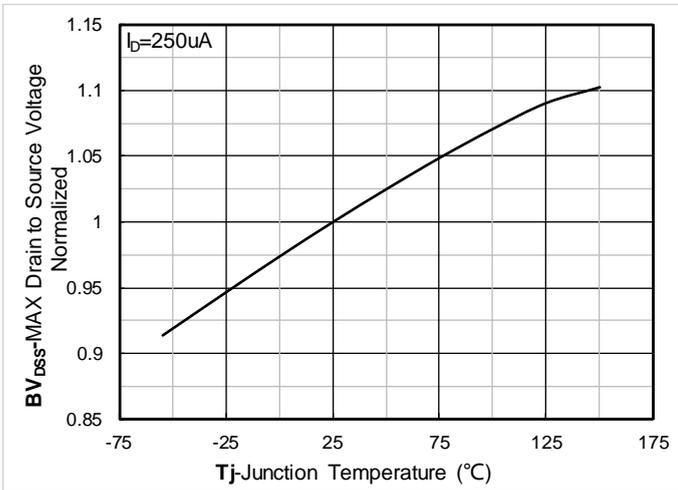


Figure 9. Normalized breakdown voltage

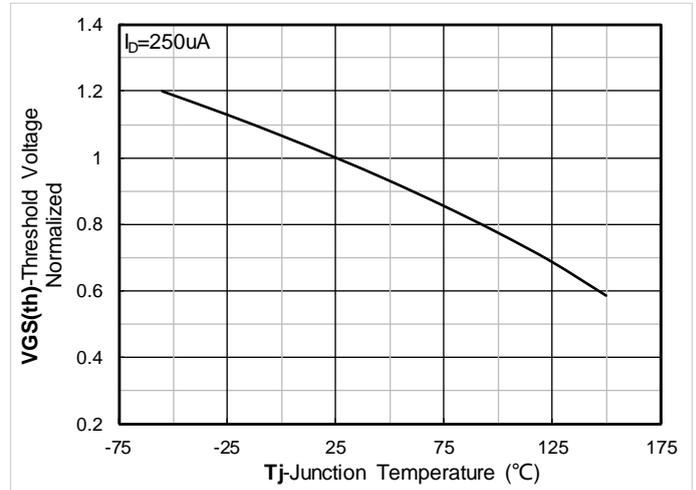


Figure 10. Normalized Threshold voltage

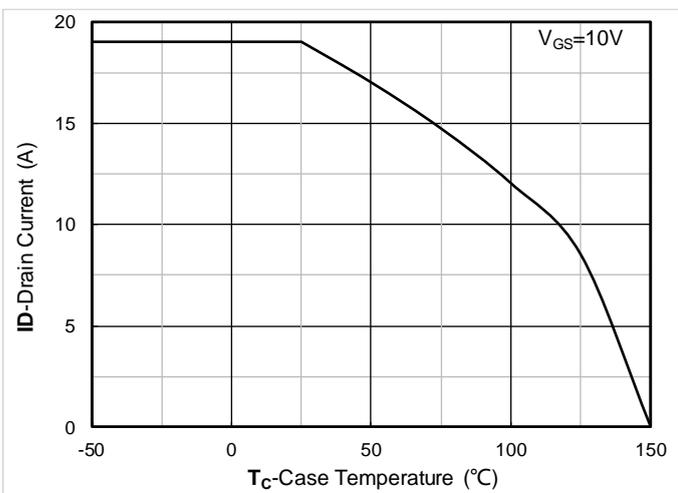


Figure 11. Current dissipation

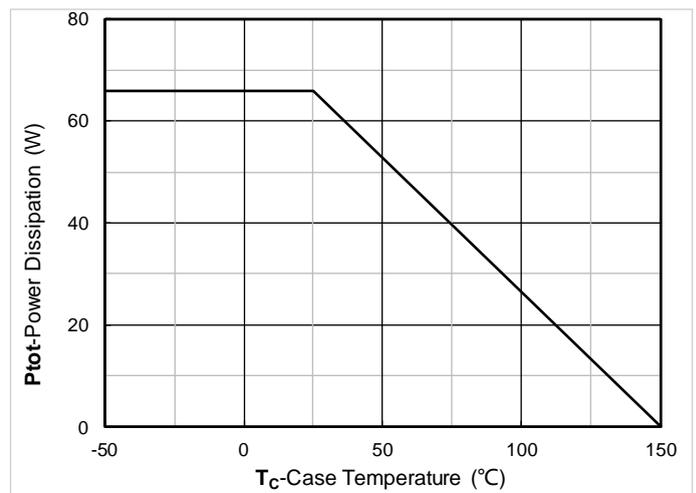


Figure 12. Power dissipation



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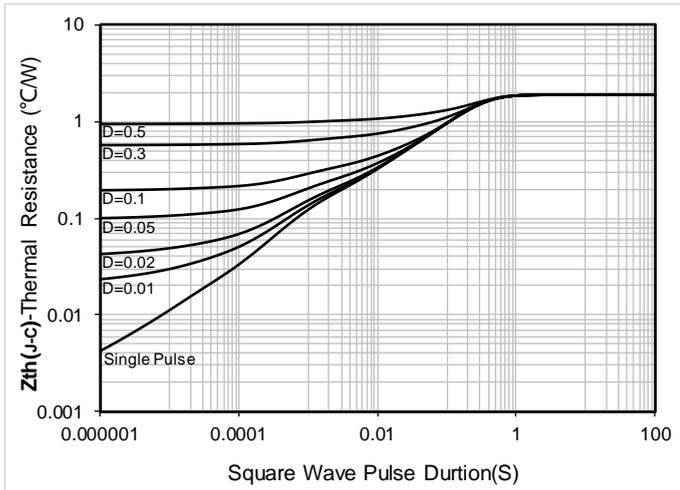


Figure 13. Maximum Transient Thermal Impedance

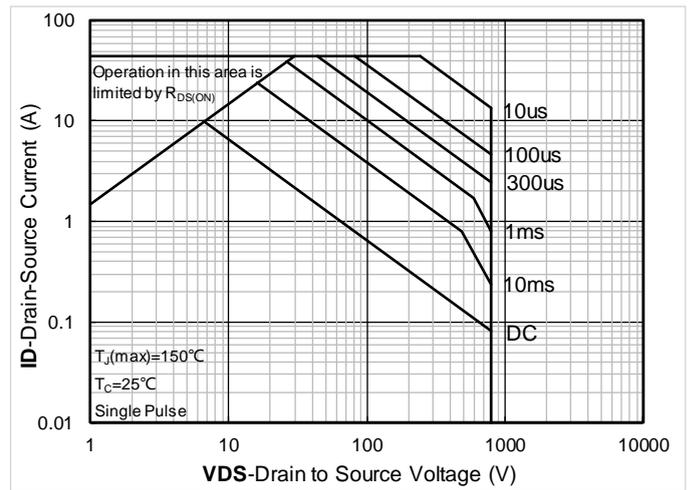


Figure 14. Safe Operation Area

## ■ Test Circuits & Waveforms

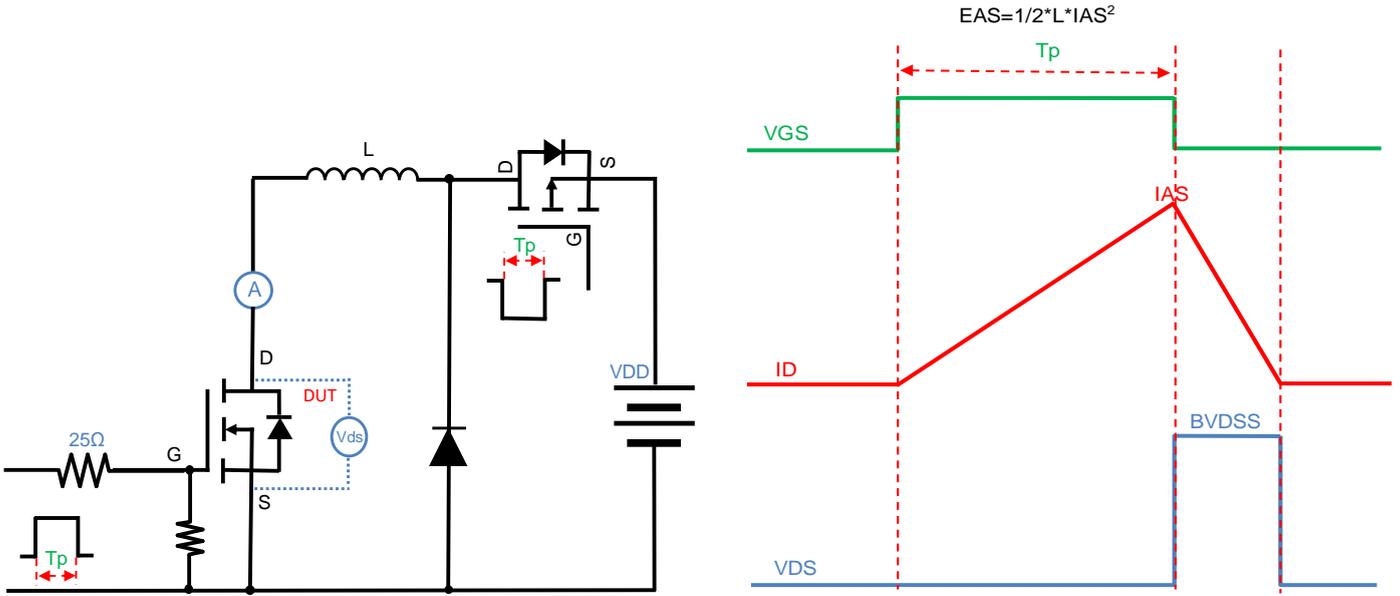


Figure A. Unclamped Inductive Switching (UIS) Test Circuit & Waveform

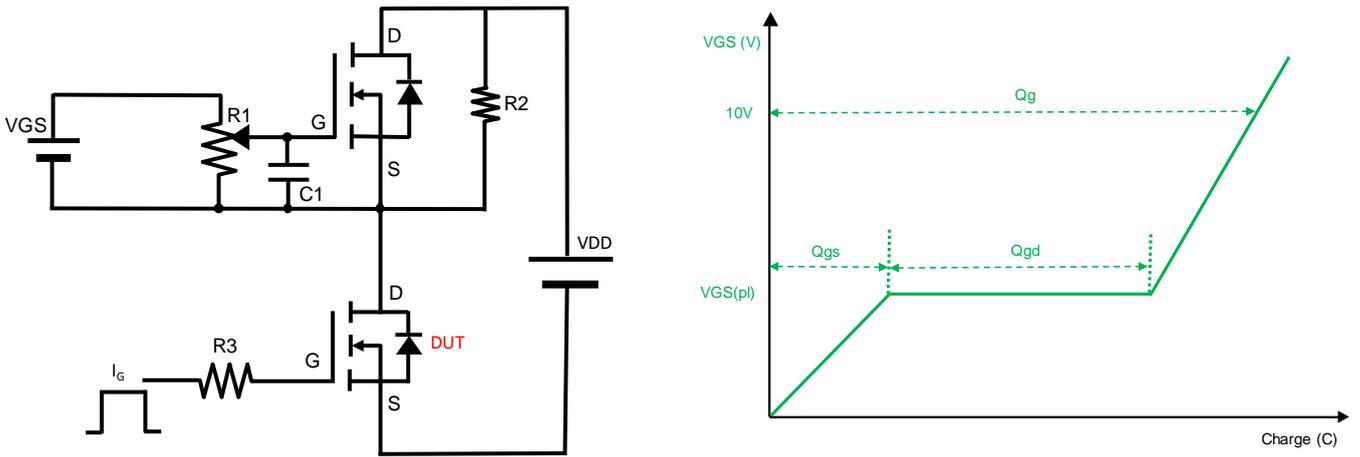


Figure B. Gate Charge Test Circuit & Waveform

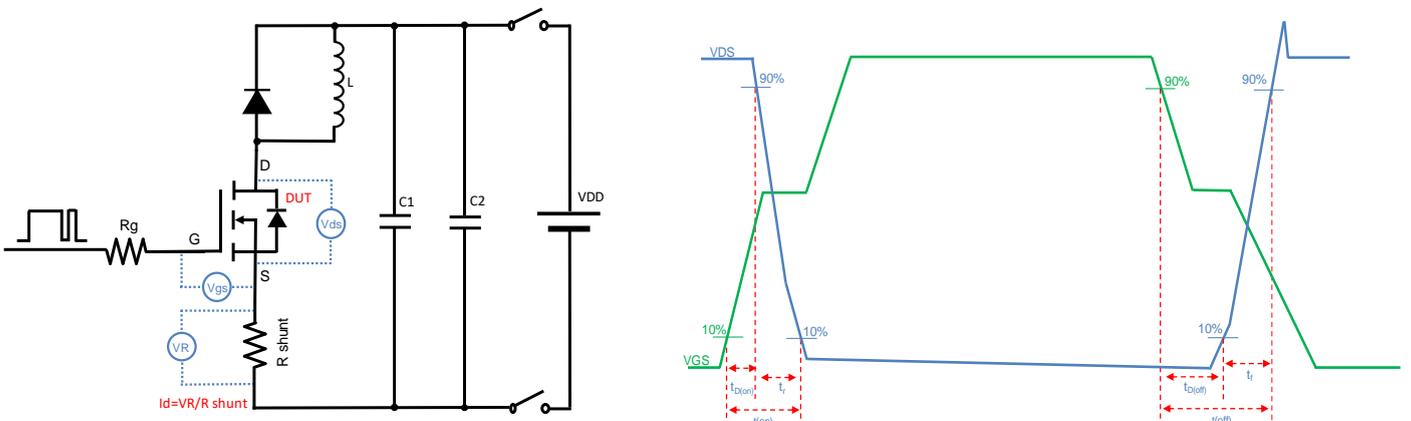


Figure C. Resistive Switching Test Circuit & Waveform

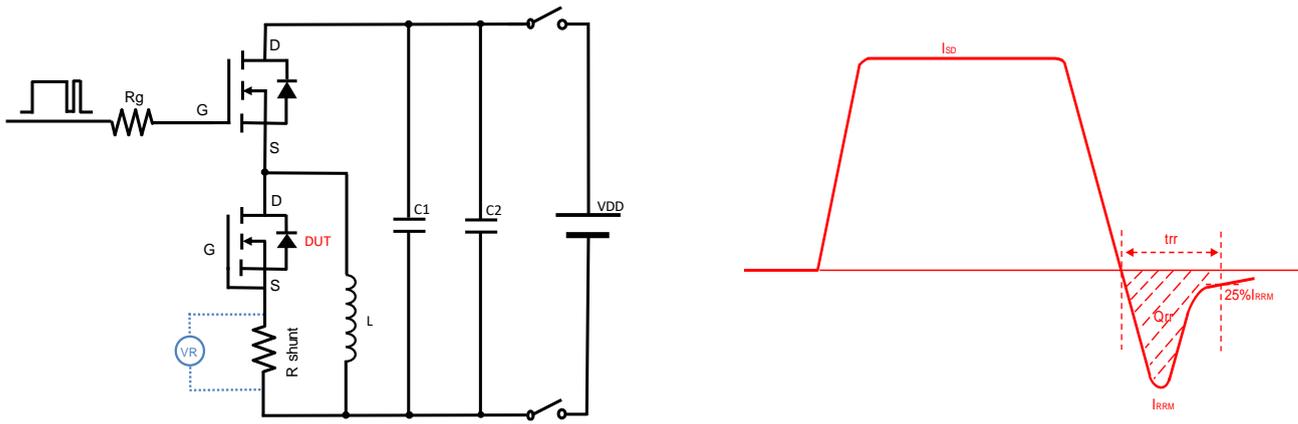
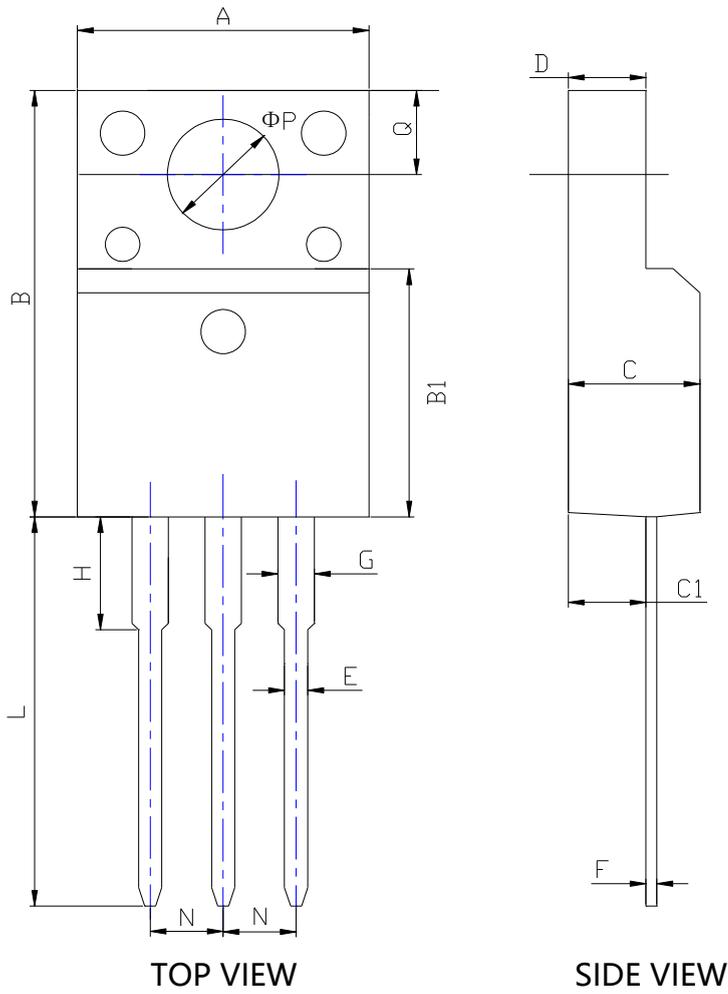


Figure D. Diode Recovery Test Circuit & Waveform



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## ■ ITO-220AB-C Package information



SYMBOL	DIMENSIONS			
	INCHES		Millimeter	
	MIN.	MAX.	MIN.	MAX.
A	0.382	0.406	9.700	10.300
B	0.610	0.634	15.500	16.100
B1	0.354	0.370	8.990	9.390
C	0.177	0.193	4.500	4.900
C1	0.102	0.116	2.600	2.950
D	0.092	0.108	2.340	2.740
E	0.028	0.035	0.700	0.900
F	0.016	0.024	0.400	0.600
G	0.044	0.056	1.120	1.420
H	0.106	0.126	2.700	3.200
L	0.496	0.535	12.600	13.600
N	0.092	0.108	2.340	2.740
Q	0.124	0.140	3.150	3.550
$\Phi P$	0.118	0.130	3.000	3.300

NOTE:  
1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.  
2. TOLERANCE 0.1mm UNLESS OTHERWISE SPECIFIED.



## YJF210C80BZJ

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